# 參考文獻

[1] 李树梓，2002，「應用類神經網路於製程平均值變化之偵測」，元智大學工業
工程與管理學系碩士班碩士論文。

[2] 徐偉晉，2001，「利用 RBF 網路建構相關性製程回饋與管制模式-以積層陶瓷
電容晶片切割作業為例」，朝陽科技大學工業工程與管理系碩士班碩士論文。

[3] 萬維君，2001，「應用類神經網路於製程平均值變化之偵測及參數之估計」，
元智大學工業工程研究所碩士論文。

[4] 陳詩銓，2002，「相關過程之經濟調整策略」，清華大學統計學研究所碩士論
文。

[5] 盧淑蘭，2003，「運用 EPC 整合 SPC 進行自我相關性資料處理之探討」，雲
林科技大學工業工程與管理系碩士班碩士論文。

[6] Alwan, L. C. and Roberts, H. V. (1988). "Time-Series Modeling for Statistical
Process Control," *Journal of Business & Economic Statistics*, Vol. 6, pp. 87-95.

[7] Bagshaw, M. and Johnson, R.A. (1975). "The Effect of Serial Correlation
Performance of CUSUM Tests 2," *Technometrics*, Vol. 17, pp. 73-80.

[8] Box, G. E. P. and Kramer, T. (1992), "Statistical Process Monitoring and Feedback
Adjustment-a Discussion," *Technometrics*, 34(3), pp. 251-267.

[9] Cook, D. and Chiu, C. C. (1998), "Using radial Basis Function Neural Networks
to Recognize Shifts in Correlated Manufacturing Process Parameters," *IIE
Transaction*, 30, pp. 227-234.

[10] Loredo, E. J. and Connie, M. B. (2002). "Model-Based Control Chart For
Autoregressive And Correlated Data" *Quality And Reliability Engineering
International*, Vol. 18, pp. 489-496.

[11] Hotelling, H. (1931), "The Generalization of Student's Ratio". *Annals of
Mathematical Science* V. 2, pp. 360-379.

[12] Jiang, W., Tsui, K. L., and Woodall, W. H. (2000). "A New Monitoring Method：The ARMA Chart," *Technometircs*, Vol. 42, pp. 399-410.

[13] Mason, R. L., Young, J. C. and Tracy, N. D. (1995). "Decomposition of $T^2$ for Multivariate Control Chart Interpretation". Journal of Quality Technology V. 27(2), pp. 99~108.

[14] Montgomery, D. C., Keats, J. B., Runger, G. C. and Messina, W. S. (1994), "Integrating Statistical Process Control and Engineering Process Control," *Journal of Quality Technology*, 26, pp. 79-87.

[15] Montgomery, D. C., (2001), *Introduction to Statistical Quality Control*, 4th ed., John Wiley & Sons, New York.

[16] Shao, Y. E., (1998) "Integrated application of the cumulative score control chart and engineering process control," Statistical Sinica, 8, pp. 239-252.

[17] Vasilopoulos, A. V. and Stamboulis, A. P. (1978). "Modification of Control Chart Limits in the Presence of Data Correlation," *Journal of Quality Technology*, Vol. 10, pp. 20-30.

[18] West, D. A., Mangiameli, P. M. and Shaw, K. C. (1998), "Control of Complex Manufacturing Processes: A Comparison of SPC Methods with a Radial Basis Function Neural Network", *The International Journal of Management Science*, Vol. 27, pp. 349-362.

[19] Zhang, N. F. (1998). "A Statistical Control Chart for Stationary Process Data," *Technometrics*, Vol. 40, pp. 24-38.

[20] Stokes, D. and May, G. S. (2000) "Real-time control of reactive ion etching using neural networks.", *IEEE Transactions on Semiconductor Manufacturing*, 13, pp. 469-480.